



Power MOSFETS

DATASHEET

LM1A092NHP3A

N-Channel
Enhancement Mode MOSFET

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Quality Management Systems
ISO 9001:2015 Certificate

N-Channel Enhancement Mode MOSFET

Pin Description

TO-220-3L (TOP view)	Symbol	Symbol	N-Channel	Unit
		V_{DSS}	100	V
		$R_{DS(ON)-Max}$	10.7	$m\Omega$
		ID	64	A

Feature

- Fast switching speed
- Reliable and Rugged
- ROHS Compliant & Halogen-Free
- 100% UIS Tested

Applications

- Motor drivers
- DC-DC Converter

Ordering Information

Orderable Part Number	Package Type	Form	Shipping	Marking
LM1A092NHP3A	TO-220-3L	Tube	50 / Tape & Reel	1A092 <input type="checkbox"/> <input type="checkbox"/> <input type="checkbox"/> <input type="checkbox"/> <input type="checkbox"/> <input type="checkbox"/>

Absolute Maximum Ratings ($T_J=25^\circ C$ Unless Otherwise Noted)

Symbol	Parameter		N-Channel	Unit
V_{DSS}	Drain-Source Voltage	$T_c=25^\circ C$	100	V
V_{GSS}	Gate-Source Voltage		± 20	
T_J	Maximum Junction Temperature		150	$^\circ C$
T_{STG}	Storage Temperature Range		-55 to 150	$^\circ C$
$I_{DM}^{①}$	Pulse Drain Current Tested	$T_c=25^\circ C$	122	A
I_D	Continuous Drain Current	$T_c=25^\circ C$	64	A
		$T_c=100^\circ C$	41	
P_D	Maximum Power Dissipation	$T_c=25^\circ C$	83	W
		$T_c=100^\circ C$	33	
$I_{AS}^{②}$	Avalanche Current, Single pulse	$L=0.1mH$	20	A
$E_{AS}^{②}$	Avalanche Energy, Single pulse	$L=0.1mH$	20	mJ

Thermal Characteristics

Symbol	Parameter		Rating	Unit
$R_{θJC}$	Thermal Resistance-Junction to Case	Steady State	1.5	$^\circ C/W$
$R_{θJA}^{③}$	Thermal Resistance-Junction to Ambient	Steady State	62.5	$^\circ C/W$

Note ① : Max. current is limited by bonding wire

Note ② : UIS tested and pulse width are limited by maximum junction temperature $150^\circ C$

Note ③ : Surface Mounted on 1in² FR-4 board with 1oz.

N-Channel Electrical Characteristics ($T_J=25^\circ\text{C}$ Unless Otherwise Noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
Static Electrical Characteristics						
$\mathbf{BV_{DSS}}$	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}$, $I_{DS}=250\mu\text{A}$	100	-	-	V
$\mathbf{I_{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=80\text{V}$, $V_{GS}=0\text{V}$	-	-	1	μA
$\mathbf{V_{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$, $I_{DS}=250\mu\text{A}$	2	3	4	V
$\mathbf{I_{GSS}}$	Gate Leakage Current	$V_{GS}=\pm 20\text{V}$, $V_{DS}=0\text{V}$	-	-	± 100	nA
$\mathbf{R_{DS(ON)}}^{\circledast}$	Drain-Source On-state Resistance	$V_{GS}=10\text{V}$, $I_{DS}=20\text{A}$	-	8.9	10.7	$\text{m}\Omega$
		$V_{GS}=6\text{V}$, $I_{DS}=20\text{A}$	-	12.5	16	
$\mathbf{g_{fs}}$	Forward Transconductance	$V_{DS}=5\text{V}$, $I_{DS}=10\text{A}$	-	18.5	-	S
Dynamic Characteristics ^⑤						
$\mathbf{R_G}$	Gate Resistance	$V_{GS}=0\text{V}$, $V_{DS}=0\text{V}$, Freq.=1MHz	-	0.9	-	Ω
$\mathbf{C_{iss}}$	Input Capacitance	$V_{GS}=0\text{V}$, $V_{DS}=50\text{V}$, Freq.=1MHz	-	1558	-	pF
$\mathbf{C_{oss}}$	Output Capacitance		-	523	-	
$\mathbf{C_{rss}}$	Reverse Transfer Capacitance		-	55	-	
$\mathbf{t_{d(ON)}}$	Turn-on Delay Time	$V_{GS}=10\text{V}$, $V_{DS}=30\text{V}$, $I_D=1\text{A}$, $R_{GEN}=6\Omega$	-	10.4	-	nS
$\mathbf{t_r}$	Turn-on Rise Time		-	17.5	-	
$\mathbf{t_{d(OFF)}}$	Turn-off Delay Time		-	26.5	-	
$\mathbf{t_f}$	Turn-off Fall Time		-	68.9	-	
$\mathbf{Q_g}$	Total Gate Charge	$V_{GS}=6\text{V}$, $V_{DS}=50\text{V}$ $I_D=20\text{A}$	-	19.9	-	nC
$\mathbf{Q_g}$	Total Gate Charge	$V_{GS}=10\text{V}$, $V_{DS}=50\text{V}$, $I_D=20\text{A}$	-	30.1	-	
$\mathbf{Q_{gs}}$	Gate-Source Charge		-	8.8	-	
$\mathbf{Q_{gd}}$	Gate-Drain Charge		-	8.8	-	
Source-Drain Characteristics						
$\mathbf{V_{SD}}^{\circledast}$	Diode Forward Voltage	$I_{SD}=10\text{A}$, $V_{GS}=0\text{V}$	-	0.8	1.1	V
$\mathbf{t_{rr}}$	Reverse Recovery Time	$I_F=10\text{A}$, $V_R=50\text{V}$ $dI_F/dt=100\text{A}/\mu\text{s}$	-	50.8	-	nS
$\mathbf{Q_{rr}}$	Reverse Recovery Charge		-	40	-	nC

Note ④ : Pulse test (pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$).

Note ⑤ : Guaranteed by design, not subject to production testing.

N-Channel Typical Characteristics

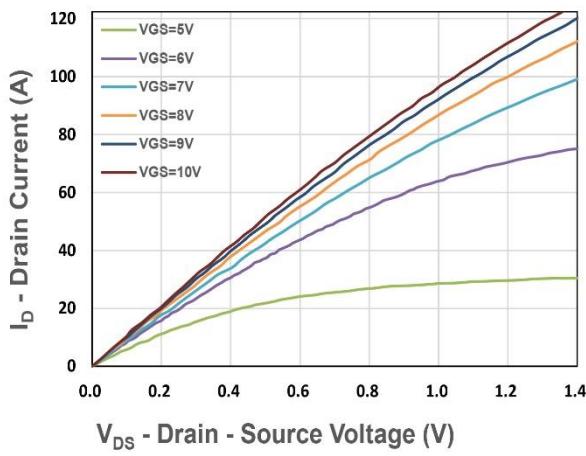


Figure 1. Output Characteristics

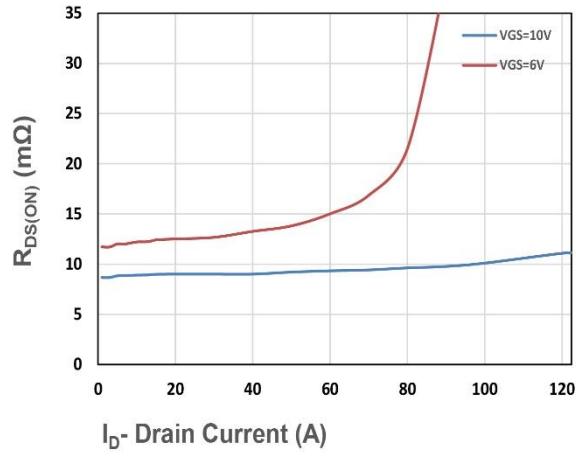


Figure 2. On-Resistance vs. ID

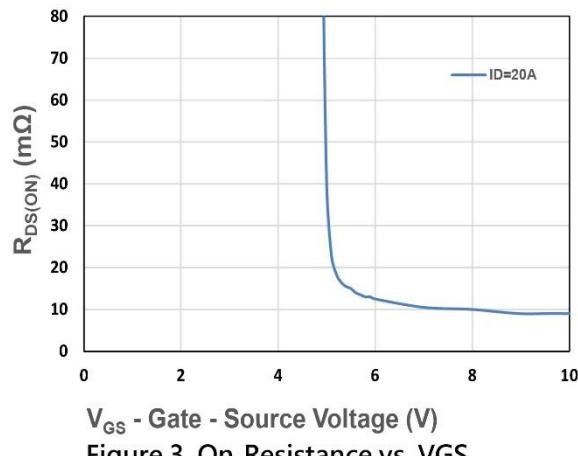


Figure 3. On-Resistance vs. VGS

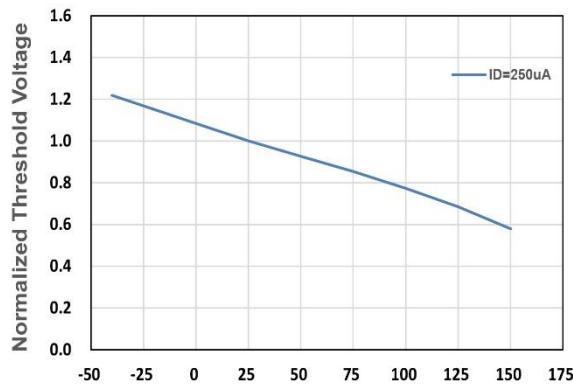


Figure 4. Gate Threshold Voltage

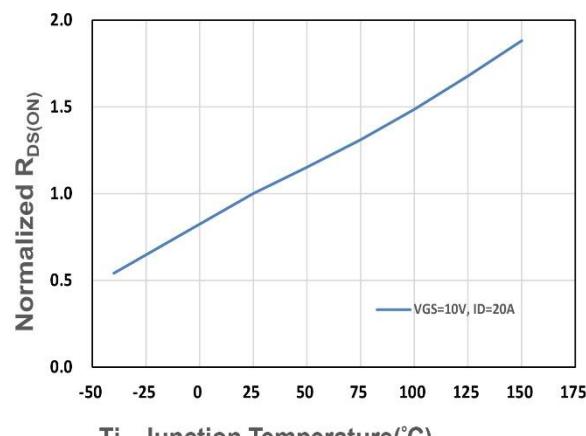


Figure 5. Drain-Source On Resistance

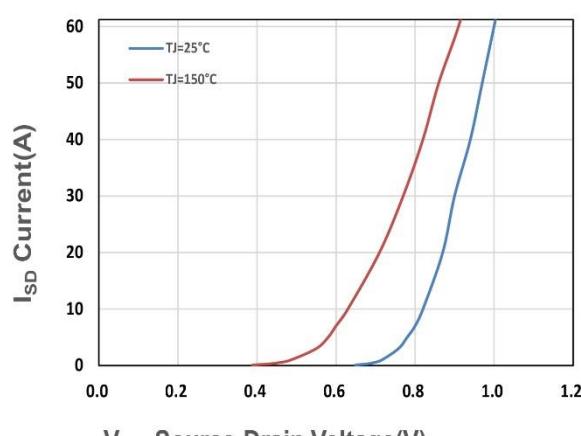
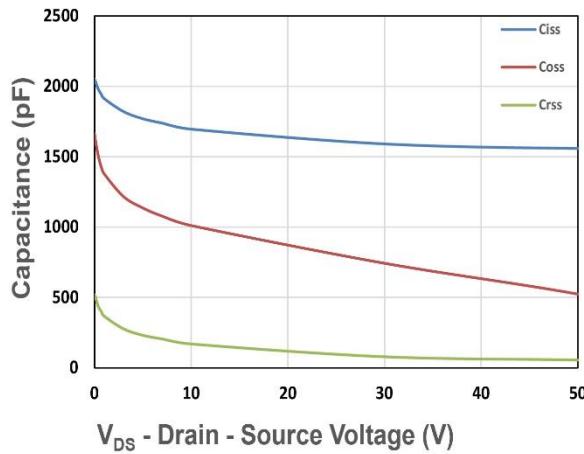


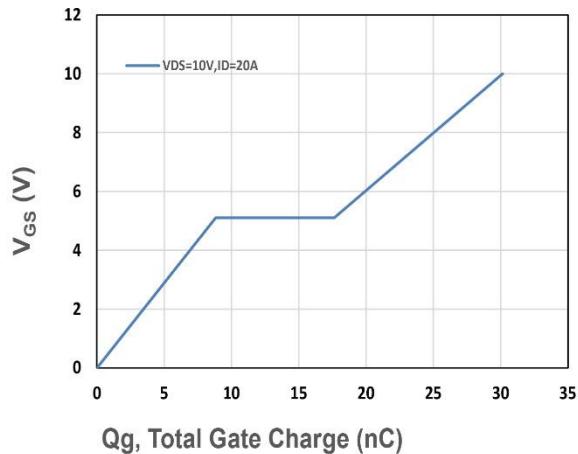
Figure 6. Source-Drain Diode Forward

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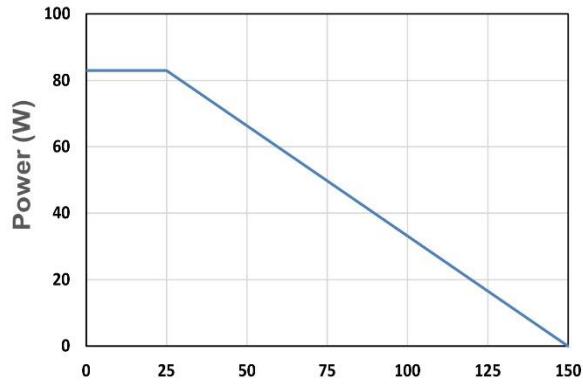
V_{DS} - Drain - Source Voltage (V)

Figure 7. Capacitance



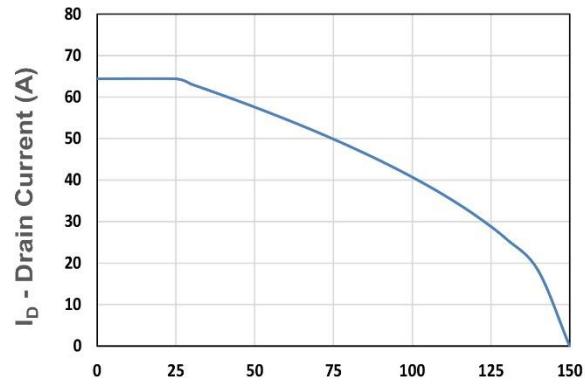
V_{GS} (V)

Figure 8. Gate Charge Characteristics



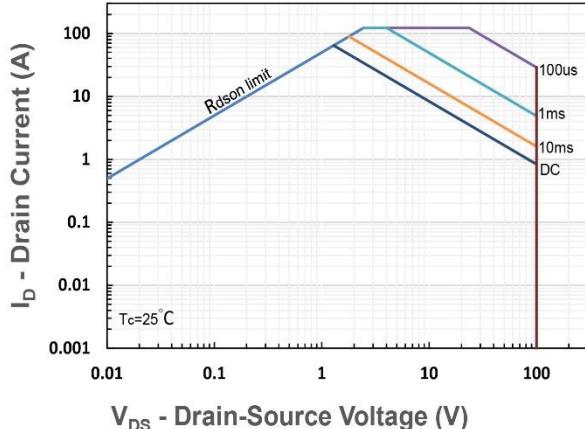
T_c - Case Temperature (°C)

Figure 9. Power Dissipation



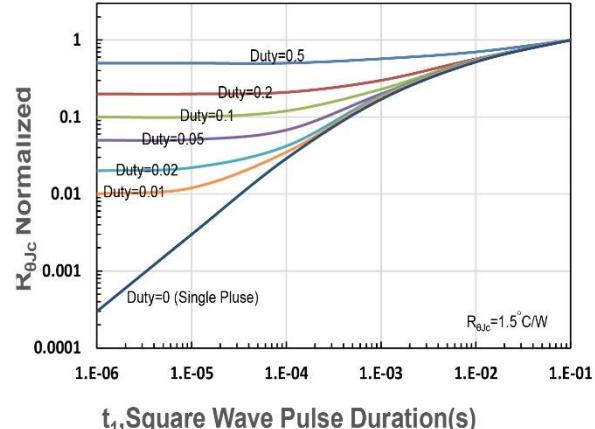
T_c - Case Temperature (°C)

Figure 10. Drain Current



V_{DS} - Drain-Source Voltage (V)

Figure 11. Safe Operating Area



t_1 , Square Wave Pulse Duration(s)

Figure 12. $R_{\theta JC}$ Transient Thermal Impedance